



CMV2000 and CMV4000 Defect specification

Change record

Issue	Date	Modification
1	10/02/10	Origination

1 CMV2000 AND CMV4000 DEFECT SPECIFICATION

1.1 DEFECT DEFINITIONS

The table below explains what is defined as a defect.

Defect name	Definition
Bad pixels in Dark Image	>6 x FPN value
Bad pixels in FPN Corrected Image	>6 x PRNU value
Bad Pixels in Saturation Image	<80% Swing
Bad Columns in FPN Corrected Image	>6 x Col pattern noise
Bad Rows in FPN Corrected Image	>6 x Row pattern noise
Bad Columns in Defect Map	>100 pixels
Bad Rows in Defect Map	>100 pixels

1.2 DEFECT LIMITS

The table below indicates the actual defect limits used during device testing.

Name	Lower Limit	Upper Limit
Dark Level	-3 Sigma	+3 Sigma
Gray Level	-3 Sigma	+3 Sigma
Saturation Level	-3 Sigma	+3 Sigma
Dark Signal	-3 Sigma	+3 Sigma
Pixel Swing	-3 Sigma	+3 Sigma
FPN	-3 Sigma	+3 Sigma
PRNU	-3 Sigma	+3 Sigma
Bad Columns		0
Bad Rows		0
Bad Pixels		100/200*
Clusters (Size 1 pixel)		100/200*
Clusters (Size 2 pixels)		0
Clusters (Size 3 pixels)		0
Clusters (Size 4 pixels)		0
Clusters (Size 5 pixels)		0
Clusters (Size 6 pixels)		0
Clusters (Size 7 pixels)		0
Clusters (Size 8 pixels)		0
Clusters (Size 9 pixels)		0
Clusters (Size 10 or more pixels)		0

*: CMV2000/CMV4000